















DRV5012

JAJSDU1 - AUGUST 2017

DRV5012 超低消費電力、デジタル・ラッチ、ホール効果センサ

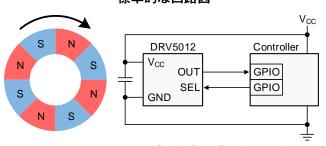
特長

- 業界最先端の低消費電力
- サンプリング・レートをピンで選択可能:
 - SEL = Low: 20Hzで1.3µA使用(1.8V)
 - SEL = High: 2.5kHzで142µA使用(1.8V)
- 1.65V~5.5VのV_{CC}範囲で動作
- 高い磁気感度: ±2mT (標準値)
- 堅牢なヒステリシス: 4mT (標準値)
- プッシュプルCMOS出力
- 小さく薄型のX2SONパッケージ
- -40℃~+85℃の動作温度範囲

2 アプリケーション

- ブラシレスDCモータ・センサ
- インクリメンタル・ロータリー・エンコーダ:
 - モータ速度
 - 機械的移動
 - 流量測定
 - ノブの回転
 - 車輪の速度
- ポータブル医療機器
- 電子ロック、電動アシスト自転車、電動ブライン ド
- 流量計
- 非接触式の起動

標準的な回路図



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3 概要

DRV5012デバイスは超低消費電力のデジタル・ラッチの ホール効果センサで、サンプリング・レートをピンで選択可 能です。

磁石のS極がパッケージの上端に近づき、Bopスレッショル ドを超えると、デバイスはLOW電圧を駆動します。磁石の N極が近づき、BRPスレッショルドを交差するまでの間、出 力はLOWに維持され、交差した時点でHIGH電圧に駆動 されます。出力を切り替えるには、N極とS極が交互に近づ く必要があり、内蔵のヒステリシスによってBopとBRPが分離 されることで、堅牢なスイッチングが行われます。

DRV5012デバイスは、内蔵の発振器を使用して磁界をサ ンプリングし、SELピンの設定に応じて20Hzまたは2.5kHz のレートで出力を更新します。このデュアル帯域幅の機能 により、システムは最小の消費電力で移動の変化を監視 できます。

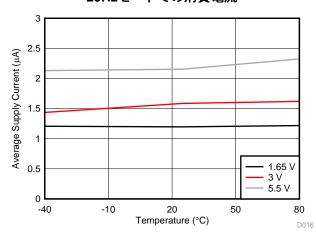
このデバイスは1.65V~5.5VのV_{CC}範囲で動作し、小型の X2SONパッケージに搭載されます。

製品情報(1)

型番	パッケージ	本体サイズ(公称)
DRV5012	X2SON (4)	1.10mm×1.40mm

(1) 利用可能なすべてのパッケージについては、このデータシートの末 尾にある注文情報を参照してください。

20Hzモードでの消費電流







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4 改訂履歴

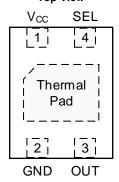
資料番号末尾の英字は改訂を表しています。その改訂履歴は英語版に準じています。

日付	改訂内容	注
2017年8月	*	初版



5 Pin Configuration and Functions

DMR Package 4-Pin X2SON With Exposed Thermal Pad Top View



Pin Functions

PIN		1/0	DESCRIPTION		
NAME	NO.	I/O	DESCRIPTION		
GND	2	_	Ground reference		
OUT	3	0	Push-pull CMOS output. Drives a V _{CC} or ground level.		
SEL	4	I	CMOS input that selects the sampling rate: a low voltage sets 20 Hz; a high voltage sets 2.5 kHz.		
V _{CC}	1	_	1.65-V to 5.5-V power supply. TI recommends connecting this pin to a ceramic capacitor to ground with a value of at least 0.1 µF.		
Thermal Pad	PAD	_	No-connect. This pin should be left floating or tied to ground. It should be soldered to the board for mechanical support.		

6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

		MIN	MAX	UNIT
Power supply voltage	V _{CC}	-0.3	5.5	٧
Power supply voltage slew rate	V _{CC}	Unl	imited	V/µs
Output voltage	OUT	-0.3	V _{CC} + 0.3	V
Output current	OUT	- 5	5	mA
Input voltage	SEL	-0.3	V _{CC} + 0.3	V
Magnetic flux density, B _{MAX}	•	Unl	imited	Т
Junction temperature, T _J			105	°C
Storage temperature, T _{stg}		- 65	150	°C

⁽¹⁾ Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

6.2 ESD Ratings

			VALUE	UNIT
		Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 (1)	±6000	
V _(ESD)	Electrostatic discharge	Charged-device model (CDM), per JEDEC specification JESD22-C101 ⁽²⁾	±750	V

⁽¹⁾ JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

⁽²⁾ JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

TEXAS INSTRUMENTS

6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	MAX	UNIT
V_{CC}	Power supply voltage (VCC)	1.65	5.5	V
Vo	Output voltage (OUT)	0	V_{CC}	V
Io	Output current (OUT)	- 5	5	mA
V_{I}	Input voltage (SEL)	0	V_{CC}	V
T_A	Operating ambient temperature	-40	85	°C

6.4 Thermal Information

		DRV5012	
	THERMAL METRIC ⁽¹⁾	DMR (X2SON)	UNIT
		4 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	159	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	77	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	102	°C/W
ΨЈТ	Junction-to-top characterization parameter	0.9	°C/W
ΨЈВ	Junction-to-board characterization parameter	100	°C/W

⁽¹⁾ For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.



6.5 Electrical Characteristics

for $V_{CC} = 1.65 \text{ V}$ to 5.5 V, over operating free-air temperature range (unless otherwise noted)

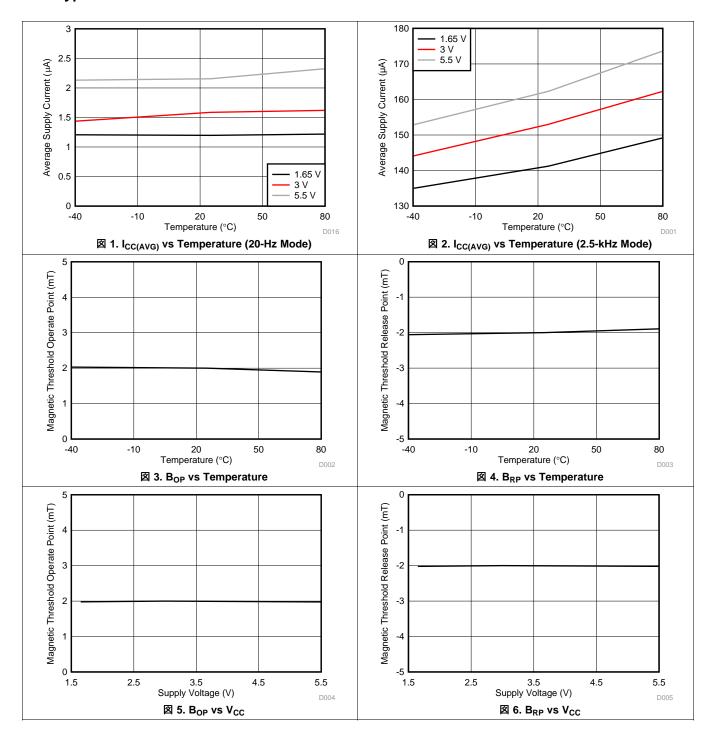
	PARAMETER	TEST C	ONDITIONS	MIN	TYP	MAX	UNIT
OUT pir	1						
V _{OH}	High-level output voltage	I _{OUT} = -1 mA		V _{CC} - 0.35	V _{CC} - 0.1		V
V _{OL}	Low-level output voltage	I _{OUT} = 1 mA			0.1	0.3	V
SEL pin	1						
V	High lovel input voltage	$V_{CC} = 1.65 \text{ to } 2.$	5 V	0.8 × V _{CC}			V
V _{IH}	High-level input voltage	$V_{CC} = 2.5 \text{ to } 5.5$	V	2			V
V_{IL}	Low-level input voltage					0.15 × V _{CC}	V
I _{IH}	High-level input leakage current	SEL = V _{CC}			1		nA
I _{IL}	Low-level input leakage current	SEL = 0 V			1		nA
DYNAM	IIC CHARACTERISTICS						
f_S	Frequency of magnetic sampling	SEL = Low		13.3	20	37	Hz
'S		SEL = High		1665	2500	4700	112
+-	Deviced of manufaction controlling	SEL = Low		27	50	75	ms
t _S	Period of magnetic sampling	SEL = High		0.21	0.4	0.6	1115
		V _{CC} = 1.8 V	SEL = Low		1.3		
		v _{CC} = 1.8 v	SEL = High		142		
	A	V _{CC} = 3 V	SEL = Low		1.6	3.3	μA
I _{CC(AVG)}	Average current consumption	v _{CC} = 3 v	SEL = High		153	370	μА
		\\\ - 5 \\	SEL = Low		2		
		$V_{CC} = 5 V$	SEL = High		160		
I _{CC(PK)}	Peak current consumption				2	2.7	mA
t _{ON}	Power-on time (see 図 11)				55	100	μs
t _{ACTIVE}	Active time period (see 🗵 11)				40		μs

6.6 Magnetic Characteristics

for V_{CC} = 1.65 V to 5.5 V, over operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
B _{OP}	Magnetic threshold operate point (see 図 9)		0.6	2	3.3	mT
B _{RP}	Magnetic threshold release point (see 図 9)		-3.3	-2	-0.6	mT
B _{HYS}	Magnetic hysteresis: $ B_{OP} - B_{RP} $		2	4		mT

6.7 Typical Characteristics





7 Detailed Description

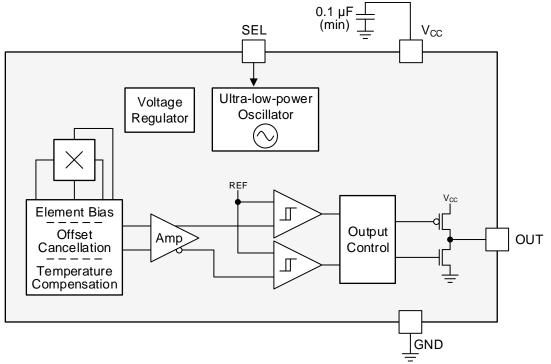
7.1 Overview

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The DRV5012 device is a magnetic sensor with a digital output that latches the most recent pole measured. Applying a south magnetic pole near the top of the package causes the output to drive low, a north pole causes the output to drive high, and the absence of a magnetic field causes the output to continue to drive the previous state, whether low or high.

The device integrates a Hall effect element, analog signal conditioning, and a low-frequency oscillator that enables ultra-low average power consumption. By operating from a 1.65-V to 5.5-V supply, the device periodically measures magnetic flux density, updates the output, and enters a low-power sleep state. A logic input pin, SEL, sets the sampling frequency to 20 Hz or 2.5 kHz with a tradeoff in power consumption.

7.2 Functional Block Diagram



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7.3 Feature Description

7.3.1 Magnetic Flux Direction

The DRV5012 device is sensitive to the magnetic field component that is perpendicular to the top of the package (as shown in ☑ 7).

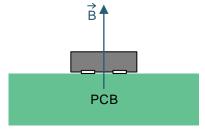


図 7. Direction of Sensitivity

TEXAS INSTRUMENTS

Feature Description (continued)

Magnetic flux that travels from the bottom to the top of the package is considered positive in this data sheet. This condition exists when a south magnetic pole is near the top of the package. Magnetic flux that travels from the top to the bottom of the package results in negative millitesla values.

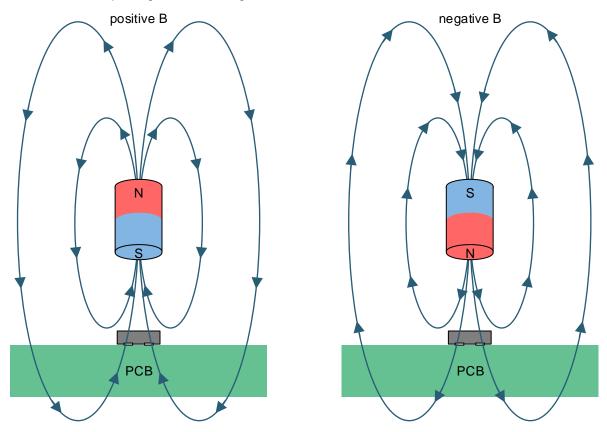


図 8. Flux Direction Polarity

7.3.2 Magnetic Response

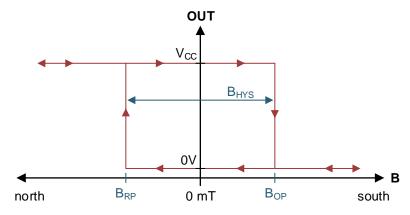


図 9. Device Functionality



Feature Description (continued)

7.3.3 Output Driver

The device features a push-pull CMOS output that can drive a V_{CC} or ground level.

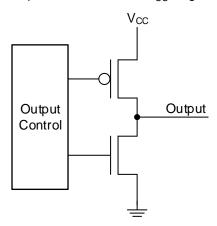


図 10. Push-Pull Output (Simplified)

7.3.4 Sampling Rate

When the DRV5012 device powers up, it measures the first magnetic sample and sets the output within the t_{ON} time. The output is latched, and the device enters an ultra-low-power sleep state. After each t_{S} time has passed, the device measures a new sample and updates the output if necessary. If the magnetic field does not change between periods, the output also does not change.

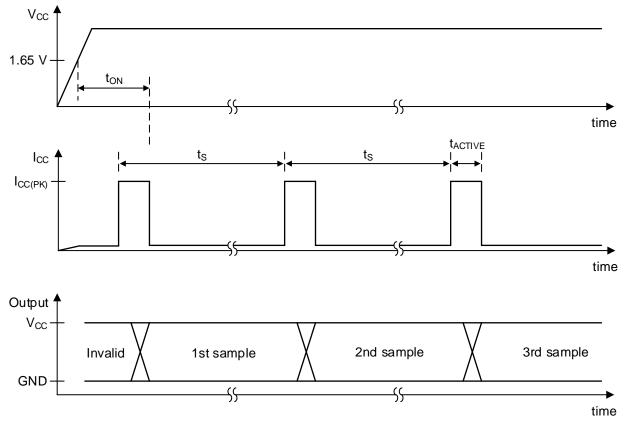


図 11. Timing Diagram

TEXAS INSTRUMENTS

Feature Description (continued)

7.3.5 SEL Pin

The SEL pin is a CMOS input that selects between two sampling rates. When the pin is low, the device samples at 20 Hz and uses low power. When the pin is high, the device samples at 2500 Hz and uses more power. The SEL pin can be tied directly high or low, or it can be changed during device operation. If the SEL voltage changes, the device detects the new voltage during the next t_{ACTIVE} time.

7.3.6 Hall Element Location

The sensing element inside the device is in the center of the package when viewed from the top. ☒ 12 shows the tolerances and side-view dimensions.

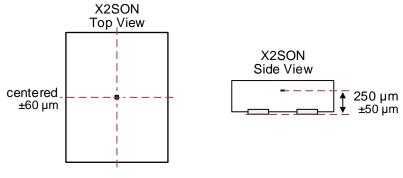


図 12. Hall Element Location

7.4 Device Functional Modes

The DRV5012 device has two operating modes, 20 Hz and 2.5 kHz, as set by the SEL pin. In both cases the *Recommended Operating Conditions* must be met.



8 Application and Implementation

注

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

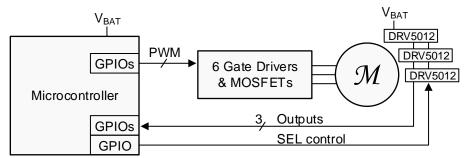
8.1 Application Information

The DRV5012 device is typically used in rotary applications for brushless DC (BLDC) motor sensors or incremental rotary encoding.

To ensure reliable functionality, the magnet should apply a flux density at the sensor greater than the maximum B_{OP} and less than the minimum B_{RP} thresholds. It is good practice to add additional margin to account for mechanical tolerance, temperature effects, and magnet variation.

8.2 Typical Applications

8.2.1 BLDC Motor Sensors Application



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図 13. BLDC Motor System

8.2.1.1 Design Requirements

For this design example, use the parameters listed in 表 1.

表 1. Design Parameters

DESIGN PARAMETER	EXAMPLE VALUE
Number of motor phases	3
Motor RPM	3000
Number of magnet poles on the rotor	6
Magnetic material	Bonded Neodymium
Peak magnetic flux density at the Hall sensors	±15 mT
Battery voltage range (V _{BAT})	2 to 3.5 V

8.2.1.2 Detailed Design Procedure

Three-phase brushless DC motors often use 3 Hall effect latch devices to measure the electrical angle of the rotor and tell the controller how to drive the 3 wires. These wires connect to electromagnet windings, which generate magnetic fields that apply forces to the permanent magnets on the rotor.

The 3 Hall sensors should be spaced across the printed-circuit board (PCB) so that they are 120° electrical degrees apart. This configuration creates six 3-bit states with equal time duration for each electrical cycle, which consists of 1 north and 1 south magnetic pole. From the center of the motor axis, the number of degrees each sensor should be spaced equals $2 / [number of poles] \times 120^\circ$. In this design example, 1 sensor is placed at 0°, 1 sensor is placed 40° rotated, and 1 sensor is placed 80° rotated. Alternatively, a $3\times$ degree offset can be added or subtracted to any sensor, meaning the third sensor could alternatively be placed at $80^\circ - (3 \times 40^\circ) = -40^\circ$.

While an ideal BLDC motor would energize the phases at the exact correct times, the DRV5012 device introduces variable lag because of the sampling architecture that achieves low power. An acceptable amount of lag can be measured by the sampling time error as a percentage of the electrical period. This design example uses 3000 RPM, which is 50 revolutions per second. Each revolution has 6 poles (3 electrical cycles), so the electrical frequency is 150 Hz, a period of 6.7 ms. The DRV5012 device in 2.5 kHz mode has a sampling period of 0.4 ms, which is 6% of the electrical period. Generally, the maximum timing error should be kept under 10% to ensure the BLDC motor spins, and timing error can reduce motor efficiency.

When the motor in this example is not driven, the SEL pins of the DRV5012 devices are set to a low voltage, and the sensor outputs are monitored for changes. If a change occurs, the microcontroller wakes the system into a higher power state and takes other appropriate action.

8.2.1.3 Application Curve

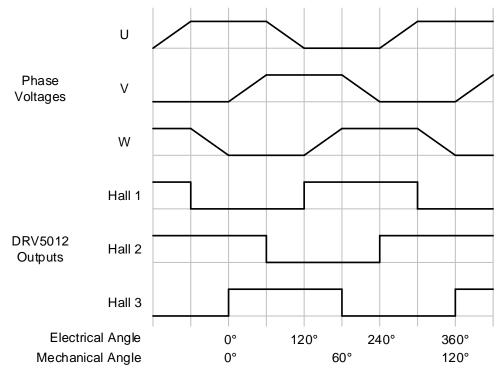
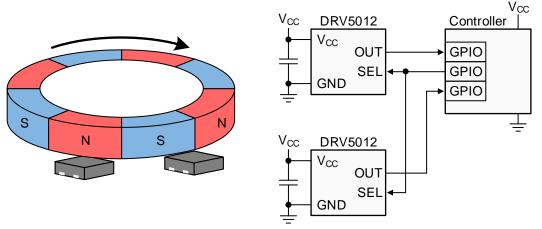


図 14. 3-Phase BLDC Motor Phase Voltages and Hall Signals



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8.2.2 Incremental Rotary Encoding Application



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図 15. Incremental Rotary Encoding System

8.2.2.1 Design Requirements

For this design example, use the parameters listed in 表 2.

2 = 2 00.9 u. u				
DESIGN PARAMETER	EXAMPLE VALUE			
RPM range	0 to 4000			
Number of magnet poles	8			
Magnetic material	Ferrite			
Air gap above the Hall sensors	2.5 mm			
Peak magnetic flux density at the sensors	±7 mT			

表 2. Design Parameters

8.2.2.2 Detailed Design Procedure

Incremental encoders are used on knobs, wheels, motors, and flow meters to measure relative rotary movement. By attaching a ring magnet to the rotating component and placing a DRV5012 device nearby, the sensor generates voltage pulses as the magnet turns. If directional information is also needed (clockwise versus counterclockwise), a second DRV5012 device can be added with a phase offset, and then the order of transitions between the two signals describes the direction.

Creating this phase offset requires spacing the two sensors apart on the PCB, and an ideal 90° quadrature offset is attained when the sensors are separated by half the length of each magnet pole, plus any integer number of pole lengths. 2 15 shows this configuration, as the sensors are 1.5 pole lengths apart. One of the sensors changes its output every 360° / 8 poles / 2 sensors = 22.5° of rotation. For reference, the TI Design TIDA-00480 uses a 66-pole magnet with changes every 2.7°.

Because the DRV5012 device periodically samples the magnetic field, there is a limit to the maximum rotational speed that can be measured. Generally, the device sampling rate should be faster than 2 times the number of poles per second. In this design example, the maximum speed is 4000 RPM, which involves 533 poles per second. The DRV5012 has a minimum sampling frequency of 1665 Hz (when the SEL pin is high), which is approximately 3×533 poles per second.

In systems where the sensor sampling rate is close to 2 times the number of poles per second, most of the samples will measure a magnetic field that is significantly lower than the peak value, since the peaks only occur when the sensor and pole are perfectly aligned. In this case, margin should be added by applying a stronger magnetic field that has peaks significantly higher than the maximum B_{OP} of the DRV5012 device.

8.2.2.3 Application Curve

Two signals in quadrature provide movement and direction information. Each 2-bit state has unique adjacent 2-bit states for clockwise and counterclockwise.

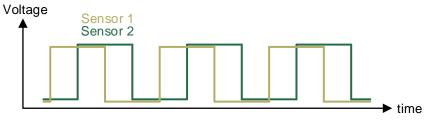


図 16. 2-bit Quadrature Output



8.3 Do's and Don'ts

Because the Hall element is sensitive to magnetic fields that are perpendicular to the top of the package, a correct magnet orientation must be used for the sensor to detect the field. 🗵 17 shows correct and incorrect orientations when using a ring magnet.

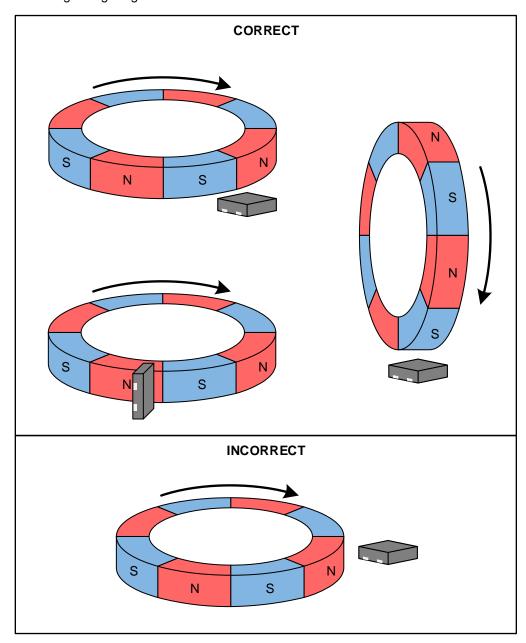


図 17. Correct and Incorrect Magnet Orientations



9 Power Supply Recommendations

The DRV5012 device is powered from 1.65-V to 5.5-V DC power supplies. A decoupling capacitor close to the device must be used to provide local energy with minimal inductance. TI recommends using a ceramic capacitor with a value of at least $0.1 \, \mu F$.

10 Layout

10.1 Layout Guidelines

Magnetic fields pass through most nonferromagnetic materials with no significant disturbance. Embedding Hall effect sensors within plastic or aluminum enclosures and sensing magnets on the outside is common practice. Magnetic fields also easily pass through most PCBs, which makes placing the magnet on the opposite side possible.

10.2 Layout Example

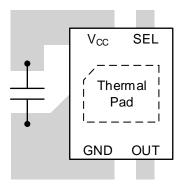


図 18. Layout Example



11 デバイスおよびドキュメントのサポート

11.1 デバイス・サポート

11.1.1 開発サポート

追加のデザイン・リファレンスについては、『車載用ホール・センサの回転式エンコーダ』TI Design (TIDA-00480)を参照し てください。

11.2 ドキュメントの更新通知を受け取る方法

ドキュメントの更新についての通知を受け取るには、ti.comのデバイス製品フォルダを開いてください。右上の隅にある「通 知を受け取る」をクリックして登録すると、変更されたすべての製品情報に関するダイジェストを毎週受け取れます。 変更の 詳細については、修正されたドキュメントに含まれている改訂履歴をご覧ください。

11.3 コミュニティ・リソース

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E™オンライン・コミュニティ TIのE2E (Engineer-to-Engineer) コミュニティ。エンジニア間の共同作 業を促進するために開設されたものです。e2e.ti.comでは、他のエンジニアに質問し、知識を共有 し、アイディアを検討して、問題解決に役立てることができます。

設計サポート *TIの設計サポート* 役に立つE2Eフォーラムや、設計サポート・ツールをすばやく見つけることが できます。技術サポート用の連絡先情報も参照できます。

11.4 商標

E2E is a trademark of Texas Instruments.

All other trademarks are the property of their respective owners.

11.5 静電気放電に関する注意事項



これらのデバイスは、限定的なESD(静電破壊)保護機能を内 蔵しています。保存時または取り扱い時は、MOSゲートに対す る静電破壊を防 ▲ ルするために、リード線同士をショートさせて おくか、デバイスを導電フォームに入れる必要があります。

11.6 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

12 メカニカル、パッケージ、および注文情報

以降のページには、メカニカル、パッケージ、および注文に関する情報が記載されています。この情報は、そのデバイスに ついて利用可能な最新のデータです。このデータは予告なく変更されることがあり、ドキュメントが改訂される場合もありま す。本データシートのブラウザ版を使用されている場合は、画面左側の説明をご覧ください。



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PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
							(6)				
DRV5012AEDMRR	ACTIVE	X2SON	DMR	4	3000	RoHS & Green	SN	Level-1-260C-UNLIM	-40 to 85	2AE	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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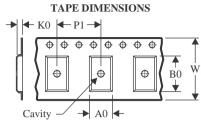
In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

PACKAGE MATERIALS INFORMATION

www.ti.com 20-Feb-2024

TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

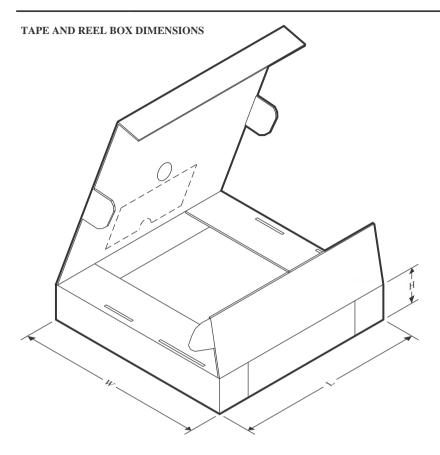


*All dimensions are nominal

Device		Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
DRV5012AEDMRR	X2SON	DMR	4	3000	179.0	8.4	1.27	1.57	0.5	4.0	8.0	Q1

PACKAGE MATERIALS INFORMATION

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*All dimensions are nominal

Ì	Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)	
ı	DRV5012AEDMRR	X2SON	DMR	4	3000	200.0	183.0	25.0	

1.1 x 1.4, 0.5 mm pitch

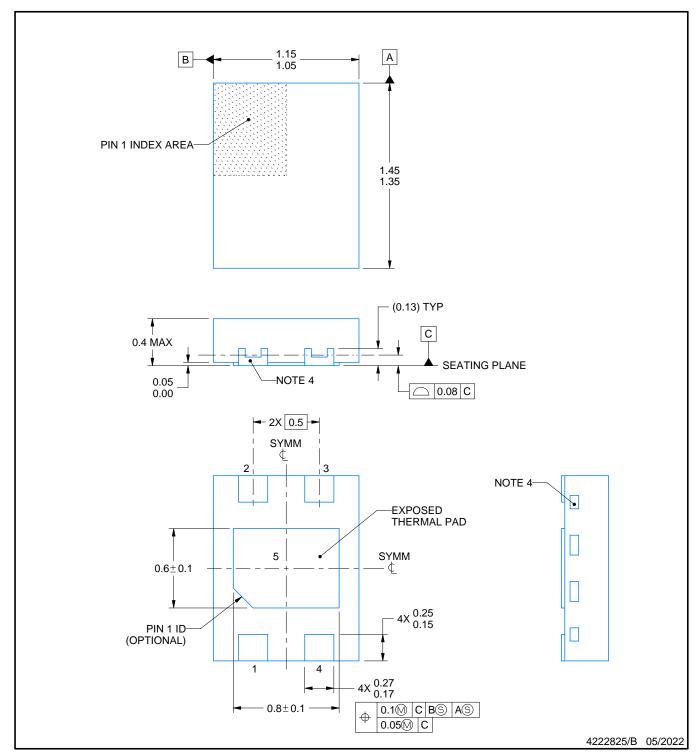
PLASTIC SMALL OUTLINE - NO LEAD

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.





PLASTIC SMALL OUTLINE - NO LEAD



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

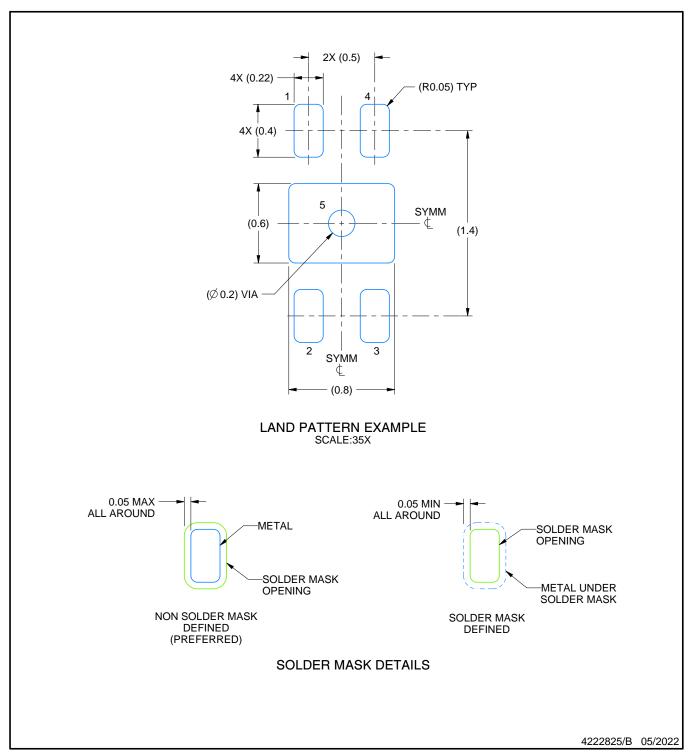
 2. This drawing is subject to change without notice.

 3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.

- 4. Quantity and shape of side wall metal may vary.



PLASTIC SMALL OUTLINE - NO LEAD

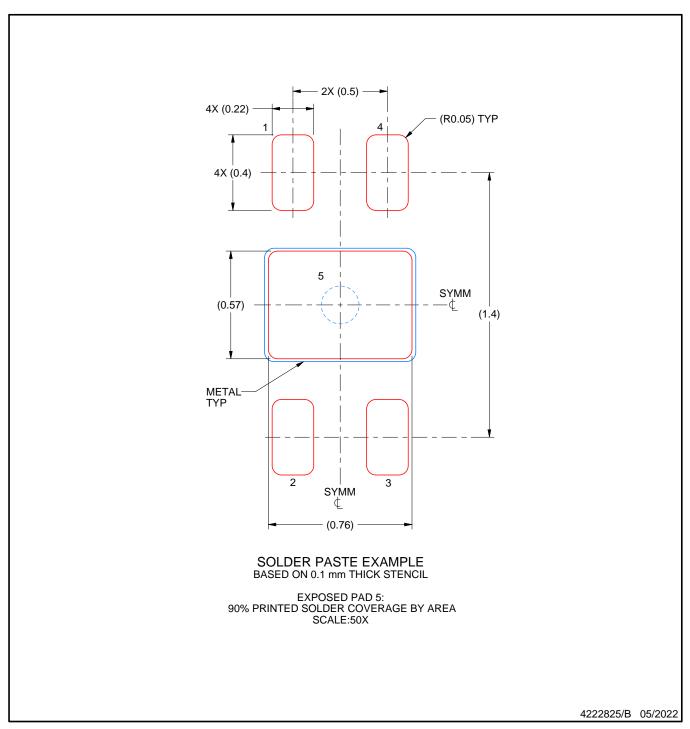


NOTES: (continued)

- 5. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- 6. Vias are optional depending on application, refer to device data sheet. If all or some are implemented, recommended via locations are shown. It is recommended that vias under paste be filled, plugged or tented.



PLASTIC SMALL OUTLINE - NO LEAD



NOTES: (continued)

7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



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